

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 240586US2	SERIAL NO. 10/623,557		
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Takashi IPPOSHI			
				FILING DATE July 22, 2003	GROUP 2822		
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME		CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA							
AB							
AC							
AD							
AE							
AF							
AG							
AH							
AI							
AJ							
AK							
AL							
AM							
AN							
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION		
AO	2002-134374	05/10/2002	JAPAN (corr. USSN 09/930,202)		YES	NO	X
AP	7-335511	12/22/1995	JAPAN (with English extract)				X
AQ							
AR							
AS							
AT							
AU							
AV							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
AW	Y. HIRANO, et al., IEEE International SOI Conference, pages 131-132, "BULK-LAYOUT-COMPATIBLE 0.18µm SOI-CMOS TECHNOLOGY USING BODY-FIXED PARTIAL TRENCH ISOLATION (PTI)", October 1999						
AX	S. MAEDA, et al., IEDM, pages 129-132, "SUPPRESSION OF DELAY TIME INSTABILITY ON FREQUENCY USING FIELD SHIELD ISOLATION TECHNOLOGY FOR DEEP SUB-MICRON SOI CIRCUITS", 1996						
AY	L.-J. HUANG, et al., Symposium on VLSI Technology Digest of Technical Papers, pages 57-58, "CARRIER MOBILITY ENHANCEMENT IN STRAINED Si-On-INSULATOR FABRICATED BY WAFER BONDING", 2001						
AZ	<input type="checkbox"/> Additional References sheet(s) attached						
Examiner	Date Considered 2/26/04						

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.